Jandel Engineering Limited

Cylindrical probe head

Jandel Engineering Limited manufactures the cylindrical probe head to be compatible with the Microposition Probe, the Multiheight Probe, the Multiheight/Microposition Probe and the Jandel Multiposition Wafer Probe, as well as some OEM mapping systems.

It can be built into customer engineered four point probe systems using an optional mounting adaptor which Jandel offers.

All Jandel probes are built to a high level of mechanical accuracy. Specifications for radii, spacing and planarity are verified by video inspection system and optical interferometer. Loads are verified by electronic force gauge. Each probe has upper and lower jewelled needle guides.

Probe spacing	0.500mm, 0.635mm, 1.00mm, 1.591mm (needle to needle)
Tolerance	+/- 10 microns
Arrangement	Linear or square array
Needles	Tungsten Carbide 0.4mm diameter (0.3mm diameter for close spacing)
Radii	12.5, 25, 40, 100, 150, 200, 300, 500 microns
Retraction to pad	0.5mm
Planarity	+/- 0.025mm or better
Loads	Fixed between 10g and 200g For 0.500mm spacing probes, the load is fixed between 60g and 100g
Leads	4-way screened cable, Teflon insulated
Electrical leakage	10^{13} ohms resistance between needles at 500 volts

Optimum probe pressure

The probe has an acrylic insulating pad on the nosepiece.

This pad should be in contact with the measured sample when a measurement is made. This ensures the needles are retracted the correct distance and the optimum indicated load is achieved.

If you require any further information on the Jandel cylindrical probe, please do not hesitate to contact us using the details below.